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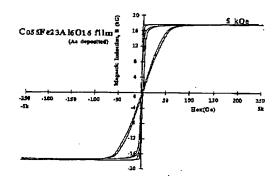
(54) MAGNETIC THIN FILM

(57) Abstract:

PROBLEM TO BE SOLVED: To provide a soft magnetic thin film with an electrical resistance and an anisotropic magnetic field, which show superior soft magnetic characteristics, even in high frequency region, and a large saturated magnetization.

SOLUTION: This magnetic thin film is formulated with a general formula $Co_{100}.X.Y.ZFeXMYOZ$ (atom%), and atomic ratios are 10-X<50, 2-Y<10, 6-Z<25 and 15-X+Y+Z<65, respectively. M is Al, Zr, Ti, Hf, Mg, Be or at least one kind of rare-earth elements whose heat of oxide of formation is -1000 kJ or above, and an anisotropic magnetic field is 20 Oe or above, an electrical resistivity value is 50 $_{\mu}\Omega$ cm or above, and saturation magnetic flux density is 16 kG or above in it.

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(54) 【発明の名称】磁性薄膜

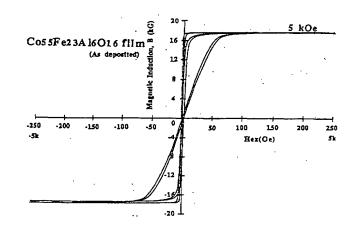
(57)【要約】

【目的】本発明は、異方性磁界が200e以上、電気比抵抗値が $50\mu\Omega$ cm以上および飽和磁束密度が16kG以上を有する高周波帯域で優れた軟磁性を示す磁性膜を提供することを目的とする。

【構成】一般式 $Co_1oo_{-X-Y-Z}Fe_XM_YO_Z$ (原子%) で示され、それぞれの原子比率が

- 1 0 < X < 5 0
- 2 < Y < 1 0
- 6 < Z < 2 5
- 15 < X + Y + Z < 65

であり、Mは酸化物の生成熱が-1000k J以上のA 1, Zr, Ti, Hf, Mg, Be, あるいは希土類元素の中の1種または2種以上の元素であり、異方性磁界が200e以上、電気比抵抗値が $50\mu\Omegacm$ 以上および飽和磁束密度が16k G以上を有することを特徴とする磁性薄膜。



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【特許請求の範囲】

【請求項1】 一般式Co₁oo-x-y-zFexMy Oz (原子%) で示され、それぞれの原子比率が

10 < X < 50

2 < Y < 10

6 < Z < 2 5

.. 1 5 < X + Y + Z < 6 5

であり、Mは酸化物の生成熱が-1000k J以上のAl, Zr, Ti, Hf, Mg, Be, および希土類元素の中の1種または2種以上の元素であり、異方性磁界が200e以上、電気比抵抗値が $50\mu\Omega$ cm以上および飽和磁束密度が16k G以上を有することを特徴とする磁性薄膜。

【請求項2】一般式Coloo-x-y-zFexAlyOz (原子%) で示され、それぞれの原子比率が

1 0 < X < 5 0

2 < Y < 10

6 < Z < 2.5

1.5 < X + Y + Z < 6.5

であり、異方性磁界が200e以上、電気比抵抗値が5 0μΩcm以上および飽和磁束密度が16kG以上を有 することを特徴とする磁性薄膜。

【請求項3】請求項1および2に記載の磁性薄膜とセラミックス薄膜とが交互に積層した多層構造を有することを特徴とする磁性薄膜。

【請求項4】請求項1および2に記載の磁性薄膜において、膜中の酸素濃度の40%未満を窒素原子で置換した、異方性磁界が200e以上、電気比抵抗値が50 μ Qcm以上および飽和磁束密度が16kG以上を有することを特徴とする磁性薄膜。

【請求項5】請求項1ないし4のいずれか1項に記載の 磁性薄膜からなる高密度磁気記録ヘッド。

【請求項6】請求項1ないし4のいずれか1項に記載の 磁性薄膜からなる1MHz以上で動作するインダクタ。

【請求項7】請求項1ないし4のいずれか1項に記載の 磁性薄膜からなる1MHz以上で動作するトランス。

【発明の詳細な説明】

[0001]

【産業上の利用分野】本発明は大きな飽和磁化、一軸磁 気異方性および電気比抵抗とを有する、高周波帯域で優 れた軟磁性を示す膜に関するものである。

[0002]

【従来の技術】近年のコンピュータの高速化や高密度記録化また移動体通信の発展に伴い、電子機器の動作周波数を高める努力や、それに伴う小型化の試みが盛んに行われている。この傾向はそれらの中で用いられる磁気デバイスにも及んでおり、そのための磁性材料の開発が検討されているが、充分な特性を有するものはまだ見いだされていない。特に、近未来の超高密度記録のハードデスクドライブ装置の記録用ヘッド材料で大きな問題にな

ることが考えられる。

【0003】一般に、1MHz以上の高周波帯域になると、金属系の磁性材料は電気抵抗が小さいために渦電流が大きくなり、高周波帯域での使用が困難になる。そのため、従来から高周波軟磁性材料としては軟磁性フェライト等で代表される酸化物の磁性材料が用いられてきた。フェライトは材料自体の電気抵抗が極めて大きいため渦電流による損失が小さい。ただし、フェライトは飽和磁化が小さいため、透磁率の共鳴周波数がそれほどあるは低率の大きさもそれほど大きくないために、その用途には多くの制限があった。そして磁気デバイスのマイクロ化においてフェライトの最も大きな、そして致命的な欠点は薄膜化が現在、全く出来ないことである。

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【OOO4】飽和磁化(Bs)が大きく、かつ髙周波帯 .城まで優れた透磁率の周波数依存性を示す磁性材料に対 する期待は、特に、高密度記録用の磁気ヘッドの分野や 髙周波帯域でのマイクロトランス材の領域で大きく、こ れまでに数多くの磁性材料、例えば、Fe-Hf-C (長谷川、斎藤:電子情報通信学会技術研究報告: MR 89-12 (1989)) そしてFe-Ta-N (名 古、榊間、井原:日本応用磁気学会誌、15、365 (1991)) などのFe系微結晶軟磁性膜が提案され てきた。これらの材料はBsが大きいため、例えば、記 録用磁気ヘッド等においてオーバーライト特性の面で優 れており、現状での書き込み速度には十分対応できてい る。しかし、年40%の割合で記録密度が上昇している ハードデスクの昨今、数年後のさらなる高い記録密度の 記録システムでは、記録密度の上昇に伴い、ハードデス クの速度は100MHz近傍になるために、現状の軟磁 性材料では対応できなくなることが考えられる。そのた め飽和磁化が大きいこととともに、さらに高い周波帯域 まで優れた透磁率の周波数依存性を示す磁性材料が期待 されている。

[0005]

【発明が解決しようとする課題】ハードデスクの記録容 量の髙密度化や、髙周波で動作するマイクロ磁気デバイ スへの強い要望は、今後、益々増大していくものと考え られる。例えば、大容量、超高速磁気記録システムを磁 性材料の点から考えると、記録媒体(磁気デスク)とし 40 ては大きな保磁力を有する磁性膜、記録用ヘッドとして は大きな飽和磁化を有する軟磁性体、そして再生用ヘッ ドとしては応答速度の良い軟磁性材料が求められる。こ れらの問題の中で、磁気デスクは20000と以上の大 きな保磁力を有するCo-Pt-Cr膜で、再生ヘッド はスピンバルブやトンネル接合タイプのMRヘッドの開 発などでクリヤ出来る見通しがでてきた。しかし、記録 ヘッド用軟磁性膜についてはまだ適切な材料が見いださ れていない。同様の軟磁性材料に関する問題は高周波帯 50 域で動作するマイクロトランスやインダクタなどの分野

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でも持ち上がりつつある。

【0006】近年、髙密度記録用磁気ヘッド材料として 大きな飽和磁化を有するFe系軟磁性微結晶膜が開発さ れ、記録ヘッド用軟磁性膜に関する問題は既に解決され たかに見えた。確かに現有のFe系軟磁性微結晶膜はそ の大きなBsが有するが故に、大きな保磁力を有する記 録媒体に対しても優れたオーバーライト特性を示す。し かし、さらに記録密度が高くなると、透磁率の共鳴周波 数が100MHz付近の現在の磁性材料では、その透磁 率の周波数特性が問題となることが考えられる。現在で も、大型のハードデスクドライブシステムでの外周のス ピードは100MHzになんなんとしている。従って、 次世代の超高密度の小型ハードデスクシステムの磁気記 録用ヘッド材料に求められる特性は、従来の大きな飽和 磁化の他に、100MHz付近まで優れた透磁率の周波 数依存性を示すことである。そのため、軟磁性材料には 大きな飽和磁化の他に、高い電気抵抗と大きな異方性磁 界とが求められる。先に述べたFe系高Bs軟磁性微結 晶膜は、一軸磁気異方性がほとんど付与されていないた め μ は大きいが、高周波帯域での μ - f 特性は良く なく、次世代の超高密度磁気記録システムには耐えられ なくなることが容易に推察できる。以上のことから、電 気比抵抗、異方性磁界、飽和磁化とが大きく、単層膜で も高周波まで良好な透磁率の周波数依存性を示す軟磁性 薄膜材料が求められている。

【0007】本発明は上記の点に鑑みてなされたもので、高周波域まで優れた軟磁気特性を示す電気抵抗、異方性磁界および飽和磁化の大きな軟磁性薄膜を提供することを目的とする。

[0008]

【課題を解決するための手段】本発明者らは、上記の事情を鑑みて鋭意努力した結果、僅かな酸素を含むCoーFeーAl系膜に、大きな飽和磁化、電気抵抗そして異方性磁界を併せ持ち、かつ単層膜でも良好な高周波軟磁気特性を示す膜が得られることを見いだし、本発明に至ったものである。

【0009】第1の発明は、一般式Co

100-x-y-z $Fe_xM_yO_z$ (原子%) で示され、それぞれの原子比率が

10 < X < 50

2 < Y < 10

6 < Z < 2 5

15 < X + Y + Z < 65

であり、Mは酸化物の生成熱が-1000k J以上のA 1, 2r, Ti, Hf, Mg, Be, 希土類元素の中の 1種または2種以上の元素であり、異方性磁界が200 e以上、電気比抵抗値が $50\mu\Omega$ c m以上および飽和磁束密度が16k G以上を有することを特徴とする磁性薄膜。

【0010】第2の発明は、一般式Co

100-x-y-z $Fe_XAl_YO_Z$ (原子%) で示され、それぞれの原子比率が

1.0 < X < 5.0

2 < Y < 10

6 < Z < 25

15 < X + Y + Z < 65

であり、異方性磁界が 200 e 以上、電気比抵抗値が $50 \mu \Omega c$ m以上および飽和磁束密度が 16 k G以上を有することを特徴とする磁性薄膜。

【0011】第3の発明は、第1発明および第2発明に 記載の磁性薄膜とセラミックス薄膜とを交互に積層した 多層構造を有することを特徴とする磁性薄膜。

【0012】第4の発明は、第1発明および第2発明に記載の磁性薄膜において、膜中の酸素濃度の40%未満を窒素原子で置換した、異方性磁界が300e以上、電気比抵抗値が50μΩcm以上および飽和磁束密度が15kG以上を有することを特徴とする磁性薄膜。

【0013】第5の発明は、第1発明ないし第4発明の いずれか1項に記載の磁性薄膜からなる高密度磁気記録 20 ヘッド。

【0014】第6の発明は、第1発明ないし第4発明のいずれか1項に記載の磁性薄膜からなる1MHz以上で動作するインダクタ。

【0015】第7の発明は、第1発明ないし第4発明のいずれか1項に記載の磁性薄膜からなる1MHz以上で動作するトランス。

[0016]

【作用】

【0017】本発明の磁性膜が16kG以上の高飽和磁 東密度(Bs)を有するためには磁性原子としてCo単 体だけでは十分でなく、10%以上のFeで置換した合 金系である必要がある。ただし、Fe濃度が50%以上 の膜では、Bsは大きくなるが、Hkが20〇e未満に なり、最終的には磁気的等方膜になってしまう。また軟 磁性を実現するためには、膜は20nm以下の粒径の結 晶粒から構成されていることが必要であり、そのために は酸化物の生成熱が約1000k J以上のM元素(M: Al、Zr、Hf、Mg、Beあるいは希土類元素)を 2%以上含む必要がある。ただし、M元素濃度が10% 40 以上になるとBsが16kG以下になってしまう。酸素 濃度が6%以下では、M元素の酸化が不十分であり、粒 径が小さくならず、軟磁性は実現しない。一方、25% 以上では、Co-Fe元素も酸化されてしまい、磁化が 小さくなると共に、垂直磁化膜になってしまう。

【0018】本発明膜には、16k G以上のBs を示す膜で、 200μ Ω c m以上の大きな電気比抵抗を示す膜は得られなかった。しかし、磁気デバイスを作製するときに必要とされる膜厚が $1\sim2\mu$ m以下であるために、渦電流損失はそれほど大きくならない。ただし、それを3000 補う意味でも透磁率の共鳴周波数を1 GH 2 付近まで高

*く説明する。

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【実施例-1】RFマグネトロンスパッタ装置を用いて (Co. ₇Fe. ₃) _{9 2} Als (原子%) ターゲット

を $(Ar + O_2)$ 混合ガス雰囲気中での反応スパッタ法によりCo-Fe-Al-O薄膜を作製した。成膜条件

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める必要があり、そのためには高いBsと共に、Hkが 200eであることが望ましい。

[0019]

【実施例】以下、従来のFe系微結晶膜やナノグラニュラー構造軟磁性膜の結果などとの比較を加えながら、本発明の実施例を説明する。

【0020】本発明を具体的実施例を用いてさらに詳し * ----【0021】----

スパッタガス圧

6x10⁻³Torr

投入電力

200W

基板温度

20℃

基板

Coming#7059 (厚さ0.5mm)

膜厚

2. $0 \sim 3$. $0 \mu m$

酸素流量比

0.0~1.0%

印加磁界

1300e (一対の永久磁石)

は以下に設定した。

【0022】得られた試料の直流磁気特性を試料振動型 磁力計により測定した。結果を図1に示す。図中の2つ のデータは、成膜時の磁界の印加方向に平行(//)、 垂直 (丄) に励磁して測定した結果を表わしている。試 料は、成膜時に印加した磁界方向と平行な一軸磁気異方 性を有しており、その異方性磁界の大きさは約45〇 e と十分に大きかった。また、垂直方向の履歴曲線(Bー Hヒステリシスループ) の結果から明らかなように、ル ープの直進性が良く、膜の異方性分散が小さいことが推 察される。得られた膜の最も大きな特徴は飽和磁束密度 (Bs) の大きさであり、その値は17.8kGと非常 に大きいものであった。この膜の保磁力(Hc)は垂 直、平行共に約1.00eと小さく、軟磁性膜であるこ とを示している。直流4端子法により測定したこの膜の 電気比抵抗(p)は、約100μΩcmとほぼアモルフ ァス膜と同程度の値を示す。また図2にはパラレルライ ン法で測定した本発明膜の透磁率の周波数依存性を示 す。破線はランダウ、リフシッツの運動方程式を基本と した理論式(神保、綱島、内山:日本応用磁気学会誌、 14、289 (1990)) である。17kG以上の大 きなBsを持っているにもかかわらず、透磁率は400 MHzまで良好な周波数依存性を示し、理論式の結果と もほぼ一致している。

[0023]

【実施例-2】実施例-1と同一条件で、Co-Feターゲットに Y_2O_3 チップを貼り付けた複合ターゲットを用いてCo-Fe-Y-O膜を作製した。得られた試料について直流磁気特性と交流磁気特性とを測定した。図3には得られた膜の透磁率の周波数依存性の一例を示す。また図中には直流磁気特性の測定結果も示す。図から明らかなように、得られた膜の透磁率はCo-Fe-Al-O膜の結果と同様に、約300の値を示し、かつ良好な周波数依存性を示す。これとほぼ同様の結果が本発明の他の組成系の膜でも観察された。

[0024]

【実施例-3】従来の高電気抵抗軟磁性膜では、M原子

と酸素原子は優先的に結合して粒界を形成し、膜の磁気 特性特性を大きな影響を与えていることが知られてい る。本発明膜の磁気特性に及ぼすMyOzの濃度の効果 を明らかにするために、実施例-1と同一条件で、Co とFeとの比を一定として、N濃度のみをOから15% 20 まで変化させた合金ターゲットを用いてCo-Fe-A 1-O膜を作製した。直流磁気特性の測定結果から求め たBsの結果を図4に示す。分析の結果、得られた膜中 のA1と酸素の濃度比はほぼ1:3であり、図面の中で は(A1.250.75)として表示した。膜中の(A 1. 25O. 75) 濃度 (y+z) が増加しても、Co - Fe-Al-O膜のBsの減少は(Al-O)原子に よる単純希釈として計算した場合のそれと比較すると小 さい。本発明膜では生成熱の大きなNが選択的に酸素と 結合し、Al-O化合物を作るためCo-Feは遊離 し、Co-Fe濃度が変わっても大きな磁気モーメント を維持しているものと推察される。このように本発明膜 はA1と酸素が膜中に共存することによってA1とCo -Feとの合金化を妨げ、大きなBsを広範囲の(Al -O) 濃度で実現している。

【0025】次に、これらの膜の電気比抵抗(p)をA 1 濃度で整理した結果を図5に示す。pの増加率は膜の 組成系でそれほど大きな差異は見られない。本発明膜の pは(A1-O)濃度の増加と共にほぼ直線的に増大 し、25%(A1-O)以上では $100\mu\Omega$ cmを越え 40 る。このような大きなpには本発明膜のA1とOとが粒 界を形成することと、膜の結晶粒を小さくすることの2つが寄与しているものと推察される。

【0026】またCo-Fe-Al-O膜のHcは図6に示す。図から明らかなように、(Al-O)濃度の増加と共に、Hcは著しく小さくなり、広い(Al-O)濃度範囲で20e以下の値を示す。このように、本発明膜はAlと酸素が膜中に共存することによって良好な軟磁性が実現しているものと推察される。なお、その起源については構造の項で考察する。

0 【0027】本発明膜の異方性磁界(Hk)を(Al-

〇)濃度で整理した結果を図7に示す。軟磁性を示す範囲での本発明膜のHkは(Al-O)濃度の増加と共に増大し、例えば、20%以上の(Al-O)を含む膜では約300e以上のHkが実現する。

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【0028】図4、5、7の結果から明らかなように、本発明膜ではBs,p,Hkの値を膜中の(Al-O)- 機度を選ぶことにより、ほぼ一義的にに決めることが出来る。

【0029】本発明膜における特性のAlおよび〇濃度の影響を明らかにするために、膜の構造をX線回折法により調べた。なお、AlとOのそれぞれの原子の影響を明らかにする目的で、膜組成の表現を(Co. τ Fe. 3)100-y-zAlyOzで示す。図8には比較例の(Co. τ Fe. 3)100-y-zAlyE(Co. τ Fe. 3)100-y-zAlyE(a)と本発明膜である(Co. τ Fe. 3)100-y-zAly Oz膜(b)の回折図形を示す。(Co. τ Fe. 3)100-y-zAly Oz膜(b)の回折図形を示す。(Co. τ Fe. 3)100-yAly 膜は基本的にBCC構造を有し、Al 濃度を変えても回折図形にはそれほど大きな変化が見られない。一方、本発明膜では(Al-O)濃度によって結晶配向や線幅に大きな変化が観察される。すなわち、Al濃度の増加と共に(110)面が優先配向になり、かつ線幅が広くなる。

【0030】これらの回折図形の結果を結晶粒径(D)と面間隔(d)で整理したのが図9、10である。なお、DはSherrerの式を用いて計算した値である(カリテー(松村源太郎訳): X線回折要論、(株)アグネ、1980)。Co-Fe-Al膜のDは、Al濃

度の増加と共にしだいに増加するのに対して、酸素を含 む本発明膜のDはCo-Fe-Al膜のそれと比較する と全体的に小さく、かつA1濃度の増加と共に減少する 傾向を示し、10%A1以上の膜で急激に小さくなり、 その値は50Å以下になる(図9)。このような小さな 粒径を持つことが、Herzerの微結晶モデル (G. Herzer: IEEE Trans. onMag. 2 6 1397 (1990)) を満足し、軟磁性を示す主 な原因になっているものと考えられる。またCoーFe 10 からなる結晶粒がBCC構造を有しているために、膜の 容易磁化方向が面内に存在するようになり、軟磁性化に 寄与しているものと推察できる。このような膜構造はA 1の選択酸化に起因しているものと考えられる。すなわ ち、本発明でも成膜中にAlがスパッタガス中の酸素と 優先的に結び付き膜中の粒界を形成し、かつA1濃度の 増加と共に粒界が多くなるために結晶粒が微細化するも のと考えられる。この考えは図10によって支持され る。本発明膜の面間隔dはAl濃度が増加してもほとん ど変化しないのに対して、Co-Fe-AlのそれはN 濃度の増加と共に増大する。この増加はAlがCo-F e 格子間に入り、格子間距離を膨張させるためと考えら れる。一方、本発明膜ではAl濃度が増大しても酸素と 結び付いて粒界を形成し、Co-Fe格子間にはA1原 子が入らないため、格子面間隔は変化しないものと考え られる。

[0031]

【表1】

特開平10-270246

•	Λ	

(6) 特開平10-						
9	特開平10-					
組成(原子%)	Bs (kG)	ρ (μΩcm)	Hk (Oe)	Hc (Oe)		
CossFez3Al6O16 X	18	98	45	1.2		
Cos3Fe22AleO19 .y	17	120	52	1.0		
Co50Fe32Al4O14 Y	19	76	42	2.4		
CossFe10Al9O22 Y	16	180	63	2.1		
Co54Fe24Al5O14N3 ×	18	88	44	1.8		
Cos3Fe22Zr7O18 ×	18	100	38	1.6		
Cos8Fe24Hi5O13 ×	19	62	36	2.2		
CoseFe30Mg4O10	20	58	28	2.3		
Co52Fe22Y7O19	. 17	136	60	1.2		
Co60Fe27Dy3O10	20	55 .	26	2.8		
Co57Fe22Mg5O12N4	18	74	48	3.2		
Co62Fe25Y3O8N2	19	69	39	2.1		
Cos3Fe23Ti6O18 ×	19	62	35	2.6		
Co60Fe25Be4O11	20	<u>5</u> 4	23	3.6		
Co⇔Fe15Sm6O16 ×	18	110	47	2.0		
Co58Fe28Y3O11/SiO2	16	220	32	0.3		
CossFe23Al6O16/Al2O3	16	180	47	0.4		
(比較) CasoFe12Al12O26	13	750	78	0.8		
(比較)Fe-Hf-O	17	62	3	0.1		
(比較)Fe-Ta-N	17	58	2	0.1		
(比較) Co-Nb-Zr(Amo.)	10	110	30	0.2		
(比較)Fe-Si-N	18	80	1	8.0		

【0032】表1はこれまでの実施例とほぼ同様な方法 で作製した本発明の請求範囲の代表的な薄膜の代表例の 測定結果を、Bs, p, Hk, Hcで整理したものであ る。また比較例として従来の軟磁性膜の結果を示す。従 来の膜でもFe-Ta-N膜のようないくつかの膜は1 7kG以上の大きなBsを示すが、Hkは著しく小さ い。一方、Co系高電気抵抗膜は大きなHkとpを示す が、Bsは15kG以下である。これに対して本発明膜 のいずれも適度な大きさのHkとpを有し、かつBs> 16kGが実現している。このように、酸化物の生成熱 の大きな元素を僅かに含むСο-Fe-M-O合金系膜 40 が軟磁性で、適度の大きさのHkとpを有し、かつ大き なBsを有する磁性材料であることが確認された。

【0033】既に述べたように、髙周波帯域での透磁率 の劣化をもたらす自然共鳴周波数(fr)はHkとBs との積に比例する。図11には本発明膜のHk、pとB sから計算で求めた $\mu - f$ 特性(a)と、 $\mu - f$ 特性か ら求めたQ-f特性(b)(Q:性能指数)の結果を示う す。比較例として既存の高Bs軟磁性膜として良く知ら れているFe-Ta-N膜の結果を併記した。図11 (a) に示すように、Fe-Ta-N膜はHkが小さい 50 ために、 μ' は大きいが、それ以上に μ'' も大きくなる

ため、100MHz付近で共鳴を起こしてしまう。一方、本発明膜は大きなBsとHkとが相乗して、 μ' はほぼ1 GHz付近まで一定の値を維持する。これらの膜を性能指数で整理した結果が図11(b)である。図から明らかなように、既知のFe-Ta-N膜と比較して、本発明膜が約1 桁の大きなQと高い共鳴周波数を有している。

[0034]

【実施例-4】さらなる高い周波数帯域まで優れた透磁 率の周波数依存性を示す膜を得るために、実施例-1と 同一条件で本発明膜とSiO2、Al2O3およびAl Nとの積層膜を作製した。磁性膜の1層当たりの膜厚を 0. 5μm以下とし、磁性層とセラミックス層との層厚 比を4対1以下になるようにした。磁化の大きさが18 k G以上の磁性膜で構成した多層膜では、多層膜化して も膜全体の磁化の大きさは15kG以下にはならない し、Hkもほとんど変化しない。多層膜化した効果は渦 電流損失の低減化に現われ、透磁率の共鳴周波数が2G Hz付近まで高くなる。多層膜化のもう一つの効果は磁 性層間の静磁結合の出現である。この結合力によって軟 磁気特性はさらに改善され、かつ異方性分散が極めて小 さくなる。以上のように、本発明膜を磁性膜として採用 した多層膜では、磁性膜のBsが大きいために、それほ どBsを減少させること無しに、優れた透磁率の周波数 依存性を示す膜を得ることが出来る。なお、表1には多 層膜化したCo-Fe-A-O/Al2O3膜およびC o-Fe-Y-O/SiO₂膜の結果を示している。

【0035】尚、本発明の磁性薄膜Co100-x-y-zFexMyOzは、上記のように高周波帯域で優れた軟磁気特性を示すが、これにV, Nb, Ta, Cr, Mo, Mn, Ni, Cu, Si, Ge, B, Ca等の1種または2種以上の元素を、高周波特性を向上する目的で添加することは本発明の技術的思想の範疇内にあり、添加しても良いことは当然である。

[0036]

【発明の効果】以上述べたように、本発明によれば、異方性磁界、飽和磁化そして電気比抵抗が共に大きい軟磁性薄膜で、高周波特性の優れた薄膜材料を提供することが出来る。本発明の薄膜は、飽和磁化が従来のFe基微結晶膜のそれに勝とも劣らない大きさと、適度の大きさの異方性磁界を有するために、共鳴周波数が高く、また電気比抵抗値も非晶質軟磁性材料と同程度の大きさであ

るために、渦電流損失が小さく、高い周波数まで、良好な透磁率の周波数特性を維持することが出来る。さらに本発明膜は、大きな飽和磁化と透磁率の優れた周波数依存性を有しているために、記録用磁気ヘッドのコア材として用いた場合には、大きな保磁力を有する超高記録密度の記録媒体でも、十分にオーバーライトすることが出来るものと考えられために、その工業的意義は大きい。

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【図面の簡単な説明】

【図1】 (Co. ¬Fe. з) s2Alsターゲットを 10 用いて作製したCossFe23AlsO1s膜のB-Hヒステリシスループ。

【図2】CossFe23AlsO1s膜の透磁率の周波数依存性を示す特性図。

【図3】Cos2Fe22Al7O19膜の透磁率の周波数依存性を示す特性図。

【図4】 (Co. 7Fe. 3) 100- (y+z) (A 1. 25O. 75) (y+z) 膜のBsと (Al-O) 濃度との関係を示す特性図。

【図5】 (Co. 7Fe. 3) 100- (y+z) (Al. 25O. 75) (y+z) 膜のpと(Al-O) 濃度との関係を示す特性図。

【図6】 (Co. 7Fe. 3) 100- (y+2) (A 1. 25O. 75) (y+2) 膜のHcと(Al-O) 濃度との関係を示す特性図。

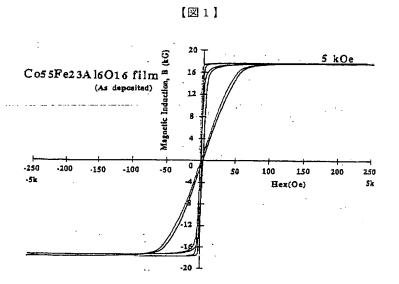
【図7】 (Co. ₇Fe. ₃) _{100- (y+z)} (A 1. ₂₅O. ₇₅) _(y+z) 膜のHkと (A1-O) 濃度との関係を示す特性図。

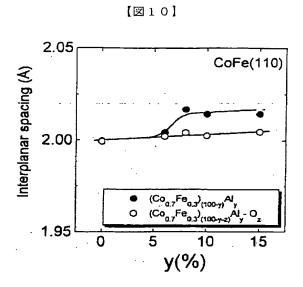
【図8】A1濃度を変えて作製した(Co.ァFe. a) 100-y-2AlyO₂膜と(Co.ァFe. a) 100-yAly膜とのX線回折図形。

【図9】 (Co. ¬Fe. з) 100-y-zAlyOz膜と (Co. ¬Fe. з) 100-yAly膜のX線回折図形から求めた結晶粒径とAl濃度との関係を示す特性図。

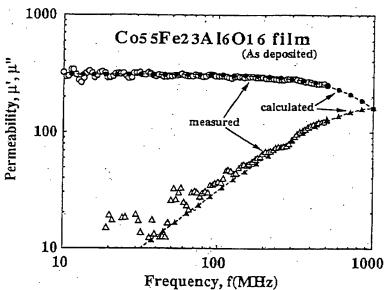
【図10】 (Co. ァFe. a) 100-y-zAly Oz膜と (Co. ァFe. a) 100-yAly膜のX 線回折図形から求めた面間隔とAl 濃度との関係を示す特性図。

【図11】本発明膜(CosoFes2Al4O14) 40 とFe-Ta-N膜の計算から求めた透磁率と性能指数 の周波数依存性を示す特性図。

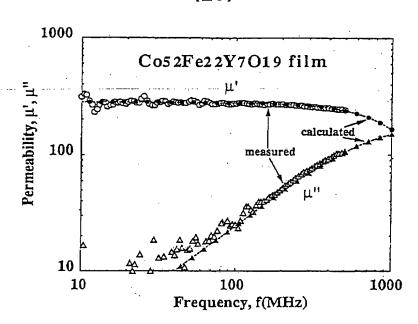


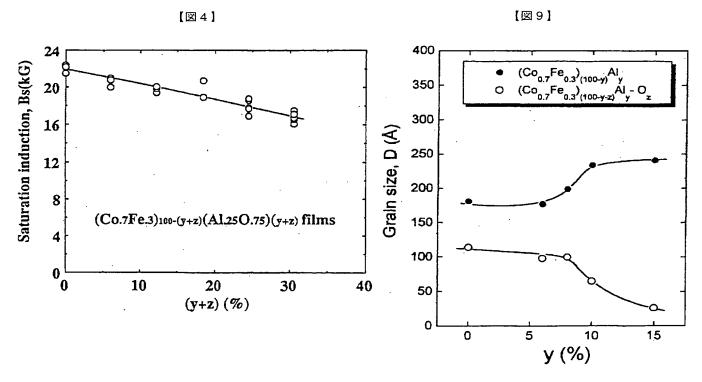






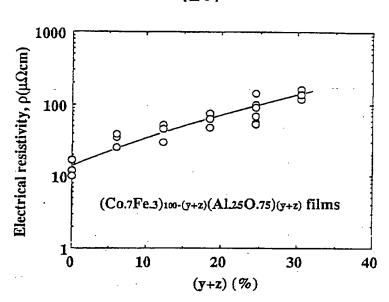
[図3]



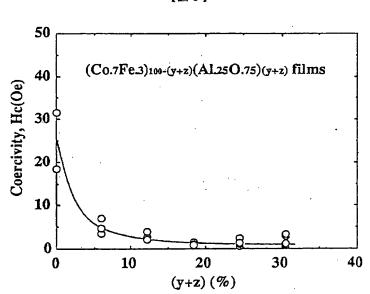






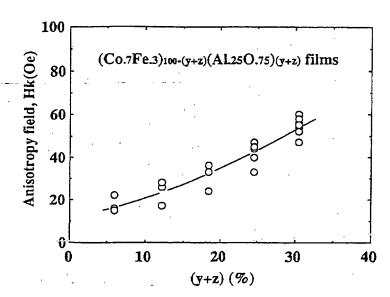


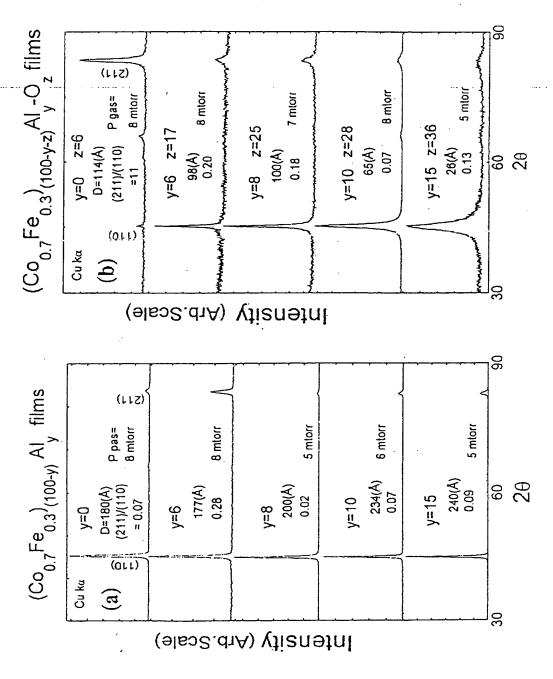
【図6】





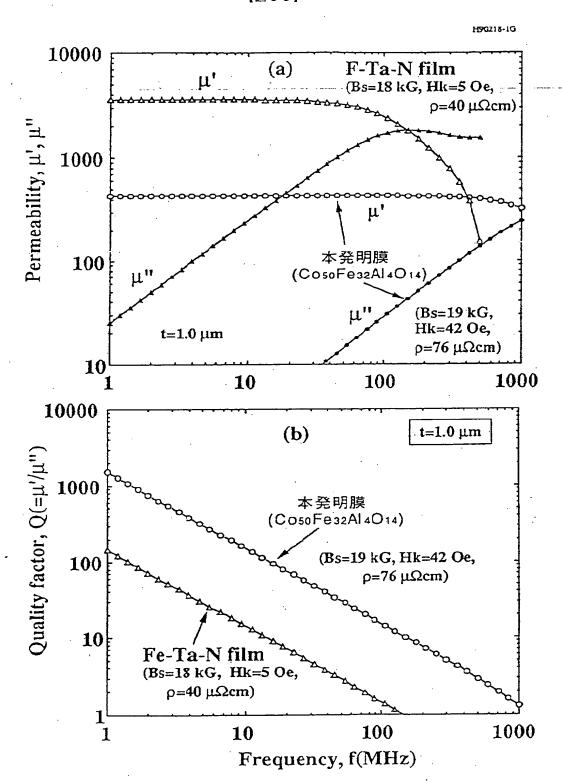
【図7】





(12)

【図11】





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CLAIMS

[Claim(s)]

[Claim 1] It is shown by general formula Co100-X-Y-ZFeXMYOZ (atomic %). Each rate of an atomic ratio is 10 < X < 502 < Y < 106 < Z < 2515 < X + Y + Z < 65. The heat of formation of M of an oxide is one sort or two sorts or more of elements in aluminum, Zr, Ti, Hf, Mg and Be of -1000 or more kJs, and rare earth elements. The magnetic thin film to which an anisotropy field is characterized by 50 or more microomegacm and saturation magnetic flux density having [20 or more Oes and electric resistivity] 16 or more kGs.

[Claim 2] The magnetic thin film to which it is shown by general formula Co100-X-Y-ZFeXAlYOZ (atomic %), each rate of an atomic ratio is 10<X<502<Y<106<Z<2515<X+Y+Z<65, and an anisotropy field is characterized by 50 or more microomegacm and saturation magnetic flux density having [20 or more Oes and electric resistivity] 16 or more kGs.

[Claim 3] The magnetic thin film characterized by having the multilayer structure in which the magnetic thin film and ceramic thin film of a publication carried out the laminating to claims 1 and 2 by turns.

[Claim 4] The magnetic thin film to which the anisotropy field which replaced less than 40% of the oxygen density in a film by claims 1 and 2 by the nitrogen atom in the magnetic thin film of a publication is characterized by 50 or more microomegacm and saturation magnetic flux density having [20 or more Oes and electric resistivity] 16 or more kGs.

[Claim 5] The high-density magnetic-recording head which becomes a claim 1 or any 1 term of 4 from the magnetic thin film of a publication.

[Claim 6] The inductor which operates above 1MHz which becomes a claim 1 or any 1 term of 4 from the magnetic thin film of a publication.

[Claim 7] The transformer which operates above 1MHz which becomes a claim 1 or any 1 term of 4 from the magnetic thin film of a publication.

[Translation done.]

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DETAILED DESCRIPTION

[Detailed Description of the Invention]

[0001]

[Industrial Application] this invention relates to the film in which the soft magnetism excellent in the high frequency band which has big saturation magnetization, a uniaxial magnetic anisotropy, and electric specific resistance is shown.

[Description of the Prior Art] The attempt of efforts to raise the frequency of operation of electronic equipment and the miniaturization accompanying it is briskly performed with improvement in the speed of a computer in recent years, the formation of high-density record, and development of mobile communications. Although this inclination has also attained to the magnetic device used in them and development of the magnetic material for it is considered, what has sufficient property is not found out yet. Especially, a bird clapper can overly be considered on the big problem of the near future with the head material for record of the hard disk drive equipment of high-density record.

[0003] Generally, if it becomes a high frequency band 1MHz or more, since the magnetic material of a metal system has small electric resistance, an eddy current will become large, and use by the high frequency band will become difficult. Therefore, the magnetic material of the oxide represented with a soft-magnetism ferrite etc. as RF soft magnetic materials from the former has been used. Since the electric resistance of a ferrite of the material itself is very large, its loss by the eddy current is small. However, since saturation magnetization of a ferrite is small, the resonance frequency of permeability is not so high, and unusual resonance etc. is observed in a low frequency band. Moreover, since the size of permeability was not so large, either, the use had many limits. And in microfilming of a magnetic device, the fatal biggest fault of a ferrite is being unable to perform thin film-ization at all now.

[0004] Saturation magnetization (Bs) the expectation for the magnetic material which shows the frequency dependence of permeability which was large and was excellent to the high frequency band Are especially large in the field of the micro transformer material in the field and high frequency band of the magnetic head for high-density record. They are many magnetic materials (Hasegawa, Saito:electronic-intelligence communication society technical research report:MR 89-12 (1989)), for example, Fe-Hf-C, and Fe-Ta-N (noted old **) until now. Sakakima, Ibara: Fe system microcrystal soft-magnetism films, such as the Magnetics Society of Japan and 15,365 (1991), have been proposed. Since such material has large Bs, they is excellent in the field of an over-writing property in the magnetic head for record etc., and can respond to the drawing speed in the present condition enough. However, by the record system of the further high recording density of several years after, since the speed of a hard disk is set to about 100MHz with elevation of recording density, by the present soft magnetic materials, it can consider that it becomes impossible to correspond these days of a hard disk when recording density is going up at a rate of 40% of years. Therefore, the magnetic material which shows the frequency dependence of permeability which was excellent to the still higher cycle band with saturation magnetization being large is expected.

[Problem(s) to be Solved by the Invention] The densification of the storage capacity of a hard disk and the strong request to the micro MAG device which operates by the RF will be considered to increase increasingly from now on. For example, if large capacity and a ultra high-speed magnetic-recording system are considered from the point of a magnetic material, as the magnetic film which has the big coercive force as a record medium (magnetic disk), the soft magnetic material which has the big saturation magnetization as a head for record, and a head for reproduction, the good soft magnetic materials of a speed of response will be called for. In these problems, a magnetic disk is the Co-Pt-Cr film which has the big coercive force of 2000 or more Oes, and the prospect which can carry out clear in a spin bulb, development of a tunnel junction type MR head, etc. came out of the reproducing head. However, a still suitable material is not found out about the soft-magnetism film for recording heads. Fields, such as a micro transformer by which the problem about the same soft magnetic materials operates by the high frequency band, and an inductor, are also being raised.

[0006] In recent years, Fe system soft-magnetism microcrystal film which has the big saturation magnetization as a magnetic-head material for high-density record was developed, and it seemed that the problem about the soft-magnetism film for recording heads was already solved. Surely, although the big Bs has Fe system soft-magnetism microcrystal film of currently possessed therefore, it shows the over-writing property which was excellent also to the record medium which has big coercive force. However, if recording density becomes high further, by the magnetic material of the present [resonance frequency / of permeability] near 100MHz, the frequency characteristic of the permeability can consider a problem and a bird clapper. Now, speed of the periphery

in a large-sized hard disk drive system is set to 100MHz chatteringly. Therefore, the property for which the head material for magnetic recording of the small hard disk system of super-high density of the next generation is asked is that the frequency dependence of permeability which was excellent to near 100MHz is shown besides the conventional big saturation magnetization. Therefore, soft magnetic materials are asked for high electric resistance and a big anisotropy field besides big saturation magnetization. Although mu' is large since, as for the Fe system quantity Bs soft-magnetism microcrystal film described previously, a uniaxial magnetic anisotropy is hardly given, the thing of the next generation for which it becomes impossible overly to bear a high-density magnetic-recording system can guess well the mu-f property in a high frequency band easily. The soft-magnetism thin film material which shows the frequency dependence of permeability also with electric specific resistance, an anisotropy field, large saturation magnetization, and a monolayer good to a RF from the above thing is called for.

[0007] this invention was made in view of the above-mentioned point, and aims at offering the electric resistance which shows ********** which was excellent to the RF region, an anisotropy field, and the big soft-magnetism thin film of saturation magnetization.

[8000]

[Means for Solving the Problem] As a result of trying hard wholeheartedly in view of the above-mentioned situation, this invention persons find out that the film which has big saturation magnetization, electric resistance, and an anisotropy field on the Co-Fe-aluminum system film containing slight oxygen, and shows RF ********* also with a good monolayer to it is obtained, and result in this invention.

[0009] The 1st invention is shown by general formula Co100-X-Y-ZFeXMYOZ (atomic %). Each rate of an atomic ratio is 10 < X < 502 < Y < 106 < Z < 2515 < X + Y + Z < 65. The heat of formation of M of an oxide is one sort or two sorts or more of elements in aluminum, Zr, Ti, Hf, Mg and Be of -1000 or more kJs, and rare earth elements. The magnetic thin film to which an anisotropy field is characterized by 50 or more microomegacm and saturation magnetic flux density having [20 or more Oes and electric resistivity] 16 or more kGs.

[0010] For 50 or more microomegacm and saturation magnetic flux density, 20 or more Oes and electric resistivity are [the 2nd invention] the magnetic thin film to which it is characterized by being shown by general formula Co100-X-Y-ZFeXAlYOZ (atomic %), for each rate of an atomic ratio being 10<X<502<Y<106<Z<2515<X+Y+Z<65, and an anisotropy field having 16 or more kGs.

[0011] The 3rd invention is a magnetic thin film characterized by having the multilayer structure which carried out the laminating of the magnetic thin film and ceramic thin film of a publication to the 1st invention and the 2nd invention by turns.

[0012] For 30 or more Oes and electric resistivity, the anisotropy field which replaced less than 40% of the oxygen density in a film by the 1st invention and the 2nd invention by the nitrogen atom in the magnetic thin film of a publication is [the 4th invention / 50 or more microomegacm and saturation magnetic flux density] the magnetic thin film to which it is characterized by having 15 or more kGs.

[0013] The 5th invention is a high-density magnetic-recording head which becomes any 1 term of the 1st invention or the 4th invention from the magnetic thin film of a publication.

[0014] The 6th invention is an inductor which operates above 1MHz which becomes any 1 term of the 1st invention or the 4th invention from the magnetic thin film of a publication.

[0015] The 7th invention is a transformer which operates above 1MHz which becomes any 1 term of the 1st invention or the 4th invention from the magnetic thin film of a publication.

[0016]

[Function]

[0017] In order for the magnetic film of this invention to have the high saturation magnetic flux density (Bs) of 16 or more kGs, just Co simple substance does not need to be enough as a magnetic atom, and it is necessary to be the alloy system replaced by 10% or more of Fe. However, Hk will be set to less than 20 Oes, and, finally Bs will become magnetic ******, although Fe concentration becomes large by 50% or more of film. Moreover, in order to realize a soft magnetism, a film needs to consist of crystal grain with a particle size of 20nm or less, and, for that, the heat of formation of an oxide needs to contain M element (M:aluminum, Zr, Hf, Mg and Be, or rare earth elements) of about 1000 or more kJs 2% or more. However, Bs will be set to 16 or less kGs if M element concentration becomes 10% or more. 6% or less of an oxygen density is [oxidization of M element] insufficient, particle size does not become small, and a soft magnetism is not realized. On the other hand, at 25% or more, while a Co-Fe element will also oxidize and magnetization becomes small, it will become perpendicular magnetic anisotropy films. [0018] The film which shows the electric big specific resistance of 200 or more microomegacm to this invention film by the film in which Bs of 16 or more kGs is shown was not obtained. However, since the thickness needed when producing a magnetic device is 1-2 micrometers or less, an eddy current loss does not become so large. However, the meaning with which it is compensated also needs to raise the resonance frequency of permeability to near 1GHz, and it is desirable for Hk(s) to be 20Oe(s) in Bs high for that.

[0019]

[Example] Hereafter, the example of this invention is explained, adding comparison with the result of the conventional Fe system microcrystal film or a nano granular structure soft-magnetism film etc.

[0020] this invention is explained in more detail using a concrete example.

[Example -1] The Co-Fe-aluminum-O thin film was produced for 92(Co.7Fe.3) aluminum8 (atomic %) target using RF magnetron-sputtering equipment by reactive sputtering in the inside of mixed-gas (Ar+O2) atmosphere. Membrane formation

conditions were set as below.

[0021]

[0024]

Spatter gas ** 6x10-3Torr Injection power 200W Substrate temperature 20 degrees C Substrate Coming#7059 (0.5mm in thickness)

Thickness 2.0-3.0 micrometers Oxygen flow rate 0.0 - 1.0% Impression magnetic field 1300e (permanent magnet of a couple) [0022] The direct-current magnetic properties of the obtained sample were measured with the sample oscillatory-type magnetometer. A result is shown in drawing 1. Two data in drawing express the result excited and measured to parallel (//) and the perpendicular (**) in the impression direction of the magnetic field at the time of membrane formation. The sample had the uniaxial magnetic anisotropy parallel to the direction of a magnetic field impressed at the time of membrane formation, and the size of the anisotropy field was fully as large as about 45 Oe(s). Moreover, it is guessed that the rectilinear-propagation nature of a loop is good and membranous anisotropy distribution is small so that clearly from the result of a vertical history curve (B-H hysteresis loop). The biggest feature of the obtained film was the size of saturation magnetic flux density (Bs), and the value was very as large as 17.8kG(s). A perpendicular and parallel of the coercive force (Hc) of this film are as small as about 1.0 Oe(s), and it is shown that it is a soft-magnetism film. The electric specific resistance (p) of this film measured by the direct-current 4 terminal method shows about 100 microomegacm and a value almost of the same grade as an amorphous film. Moreover, the frequency dependence of the permeability of this invention film measured by the parallel line method is shown in drawing 2. Dashed lines are Landau and a theoretical formula (the Jinbo, Tsunashima, and Uchiyama:Magnetics Society of Japan, 14,289 (1990)) based on the equation of motion of RIFUSHITTSU. In spite of having big Bs of 17 or more kGs, permeability shows frequency dependence good to 400MHz, and is carrying out simultaneously coincidence of the result of a theoretical formula.

[Example -2] On the same conditions as an example -1, the Co-Fe-Y-O film was produced using the compound target which stuck 2OY3 chip at the Co-Fe target. Direct-current magnetic properties and alternating current magnetic properties were measured about the obtained sample. An example of the frequency dependence of the permeability of the obtained film is shown in <u>drawing 3</u>. Moreover, all over drawing, the measurement result of direct-current magnetic properties is also shown. Like the result of an Co-Fe-aluminum-O film, the permeability of the obtained film shows about 300 value, and shows good frequency dependence so that clearly from drawing. The film of the composition system of everything [result / almost same / the / as this] but this invention was also observed.

[Example -3] It joins together preferentially, M atom and an oxygen atom form a grain boundary, and having had big influence is known for the conventional high electric resistance soft-magnetism film in the membranous magnetic-properties property. in order to clarify the effect of the concentration of MYOZ exerted on the magnetic properties of this invention film, on the same conditions as an example -1, the ratio which it is with Co and Fe was set constant, and the Co-Fe-aluminum-O film was produced using the alloy target to which only N concentration was changed to 0 to 15% The result of Bs calculated from the measurement result of direct-current magnetic properties is shown in <u>drawing 4</u>. As a result of analysis, aluminum in the obtained film and the ratio of concentration of oxygen are about 1:3, and were displayed as (aluminum.250.75) in the drawing. Even if the concentration (y+z) (aluminum.250.75) in a film increases, reduction of Bs of an Co-Fe-aluminum-O film is small as compared with it at the time of calculating as simple dilution by the atom (aluminum-O). In order that N with big heat of formation may combine with oxygen alternatively and may make an aluminum-O compound from this invention film, Co-Fe separates, and even if Co-Fe concentration changes, it is imagined to be what is maintaining the big magnetic moment. Thus, when aluminum and oxygen live together in a film, this invention film barred alloying with aluminum and Co-Fe, and has realized big Bs by wide range (aluminum-O) concentration.

[0025] Next, the result which arranged the electric specific resistance (p) of these films by aluminum concentration is shown in drawing 5. The difference by the membranous composition system with so big the rate of increase of p is not seen. p of this invention film increases almost linearly with the increase in concentration (aluminum-O), and exceeds 100microomegacm above 25% (aluminum-O). It is imagined as what two, make [that aluminum and O of this invention film form a grain boundary in such big p and] membranous crystal grain small, have contributed.

[0026] Moreover, Hc of an Co-Fe-aluminum-O film is shown in <u>drawing 6</u>. With the increase in concentration (aluminum-O), Hc becomes remarkably small and shows the value below 20e by the latus (aluminum-O) density range so that clearly from drawing. Thus, this invention film is imagined to be what the good soft magnetism has realized when aluminum and oxygen live together in a film. In addition, the term of structure considers the origin.

[0027] The result which arranged the anisotropy field (Hk) of this invention film by concentration (aluminum-O) is shown in drawing 7. By the film which increases with the increase in concentration (aluminum-O), for example, contains 20% or more of (aluminum-O), Hk of about 30 or more Oes realizes Hk of this invention film in the range which shows a soft magnetism. [0028] by this invention film, by choosing the concentration (aluminum-O) in a film, the value of Bs, p, and Hk can be boiled almost uniquely, and can be decided so that clearly from drawing 4 and the result of 5 and 7

[0029] In order to clarify influence of aluminum of the property in this invention film, and O concentration, membranous structure was investigated with the X-ray diffraction method. In addition, 100(Co.7Fe.3)-yAly and 100(Co.7Fe.3)-y-zAlyOz show expression of film composition for the purpose which clarifies influence of each atom of aluminum and O. The diffraction pattern of the 100-y-ZAlyOZ film (b) which is the 100(Co.7Fe.3)-yAly film (a) and this invention film of the example of comparison (Co.7Fe.3) is shown in drawing 8. (Co.7Fe.3) A 100-yAly film has BCC structure fundamentally, and even if it changes

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aluminum concentration, a so big change is not looked at by the diffraction pattern. On the other hand, by this invention film, the big change to crystal orientation or line breadth is observed with concentration (aluminum-O). That is, a field (110) becomes priority orientation with the increase in aluminum concentration, and line breadth becomes large. [0030] Drawing 9 and 10 arranged the result of these diffraction patterns by the diameter of crystal grain (D), and the spacing (d). In addition, D is the value calculated using the formula of Sherrer (KARITE (Gentaro Matsumura translation): X diffraction ****, AGUNE, 1980). To D of an Co-Fe-aluminum film increasing gradually with the increase in aluminum concentration, on the whole, D of this invention film containing oxygen is small as compared with it of an Co-Fe-aluminum film, and the inclination which decreases with the increase in aluminum concentration is shown, it becomes small rapidly by the film more than 10% aluminum, and the value becomes 50A or less (drawing 9). Having such a small particle size satisfies the microcrystal model (G. Herzer: IEEE Trans. on Mag. 26 1397 (1990)) of Herzer, and it is considered to be the main causes which show a soft magnetism. Moreover, since the crystal grain which consists of Co-Fe has BCC structure, the membranous easy magnetization direction comes to exist in a field, and can imagine it as what has contributed to soft-magnetism-ization. It is thought that such a membrane structure originates in the selective oxidation of aluminum. That is, since aluminum is preferentially connected with the oxygen in spatter gas, and this invention also forms the grain boundary in a film during membrane formation and a grain boundary increases with the increase in aluminum concentration, it is thought that crystal grain makes it detailed. This idea is supported by drawing 10. It of Co-Fe-aluminum increases with the increase in N concentration to hardly changing, even if aluminum concentration increases the spacing d of this invention film. aluminum enters between Co-Fe grids and this increase is considered for expanding the distance between grids. On the other hand, by this invention film, even if aluminum concentration increases, in order that it may be connected with oxygen, a grain boundary may be formed and aluminum atom may not enter between Co-Fe grids, it is thought that a lattice spacing does not change.

[0031] [Table 1]

[lable l]			·	
組 成(原子%)	Bs (kG)	ρ (μΩcm)	Hk (Oe)	Hc (Oe)
CossFe23Al6O16	18	98	45	1.2
Cos3Fe22Al6O19	17	120	52	1.0
Co50Fe32Al4O14	19	76	42	2.4
CossFe10AlsO22	16	180	63	2.1
Co54Fe24Al5O14N3	18	88	44	1.8
CossFe22Zr7O18	18	100	38	1.6
Co58Fe24H/5O13	19	62	36	2.2
CoseFe30Mg4O10	20	58	28	2.3
Co52Fe22Y7O19	17	136	60	1.2
Co60Fe27Dy3O10	20	55	26	2.8
Co57Fe22Mg5O12N4	18	74	48	3.2
C062Fe25Y3O8N2	19	69	39	2.1
CossFeasTicO18	19	62	35	2.6
Co60Fe25Be4O11	20	54	23	3.6
Co63Fe15Sm6O16	18	110	47	2.0
Co58Fe28Y3O11/SiO2	16	220	32	0.3
CossFe23Al6O16/Al2O3	16	180	47	0.4
(比較) Co50Fe12Al12O26	13	750	78	8.0
(比較)Fe-Hf-O	17	62	3	0.1
(比較) Fe-Ta-N	17	58	2	0.1
(比較) Co-Nb-Zr(Amo.)	10	- 110	30	0.2

[0032] Table 1 arranges the measurement result of an old example and the example of representation of the typical thin film of the generic claim of this invention produced by the almost same method by Bs, p, Hk, and Hc. Moreover, the result of the conventional soft-magnetism film is shown as an example of comparison. Its Hk is remarkably small although some films [as / whose conventional films are also Fe-Ta-N films] show big Bs of 17 or more kGs. On the other hand, although Co system quantity electric resistance film shows big Hk and big p, Bs is 15 or less kGs. On the other hand, all of this invention film had Hk and p of a moderate size, and Bs>16kG is realized. Thus, it was checked that the Co-Fe-M-O alloy system film which contains slightly an element with the big heat of formation of an oxide is the magnetic material which has Hk and p of a moderate size by the soft magnetism, and has big Bs.

[0033] As already stated, the natural resonance frequency (fr) which brings about degradation of the permeability in a high frequency band is proportional to the product of Hk and Bs. The result of the mu-f property (a) searched for by Hk, p, and Bs to calculation of this invention film, the Q-f property (b) searched for from the mu-f property, and (Q:performance index) is shown in drawing 11. The result of the Fe-Ta-N film well known as an existing high Bs soft-magnetism film as an example of comparison was written together. Although mu' is large since an Fe-Ta-N film has small Hk as shown in drawing 11 (a), since mu" also becomes large more than it, resonance will be caused near 100MHz. On the other hand, big Bs and big Hk multiply this invention film, and mu' maintains a fixed value to near about 1GHz. The result which arranged these films by the performance index is drawing 11 (b). As compared with the known Fe-Ta-N film, this invention film has big Q and the high resonance frequency of about 1 figure so that clearly from drawing.

[Example -4] In order to obtain the film in which the frequency dependence of permeability which was excellent to the further high frequency band is shown, the cascade screen with this invention film, SiO2, aluminum2O3, and AlN was produced on the same conditions as an example -1. Thickness per layer of a magnetic film is set to 0.5 micrometers or less, and the thickness ratio of a magnetic layer and a ceramic layer was made to become 4 to 1 or less. In the multilayer which the size of magnetization constituted from a magnetic film of 18 or more kGs, even if it multilayer-izes, the size of magnetization of the whole film is not set to 15 or less kGs, and Hk hardly changes, either. The multilayer-ized effect shows up in reduction-ization of an eddy current loss, and the resonance frequency of permeability becomes high to near 2GHz. Another effect of multilayer-izing is the appearance of the magnetostatic combination between magnetic layers. ********** improves further with this bonding strength, and anisotropy distribution becomes very small. As mentioned above, in the multilayer which adopted this invention film as a magnetic film, the film in which the outstanding frequency dependence of permeability is shown can be obtained, without decreasing Bs so much, since Bs of a magnetic film is large. In addition, the result of 2OCo-Fe-A-O/aluminum3 multilayer-ized film and Co-Fe-Y-O/SiO2 film is shown in Table 1.

[0035] In addition, although magnetic-thin-film Co100-x-y-zFexMyOz of this invention shows ******** which was excellent in the high frequency band as mentioned above, to this, one sort or two sorts or more of elements, such as V, Nb, Ta, Cr, Mo, Mn, nickel, Cu, Si, germanium, B, and calcium, are sometimes added in the criteria of the technical thought of this invention in order to improve a RF property, and it is natural that you may add. [0036]

[Effect of the Invention] According to this invention, both an anisotropy field, saturation magnetization, and electric specific resistance can offer the thin film material which was described above and which excelled [thin film / soft-magnetism / large] in the RF property like. Since saturation magnetization has the anisotropy field of **, the size which is not inferior, and a moderate size in it of the conventional Fe basis microcrystal film and the thin film of this invention is a size with it, an eddy current loss is small and can maintain the frequency characteristic of good permeability to high frequency. [a high and resonance frequency and] [of the same grade / electric resistivity / as amorphous soft magnetic materials] Furthermore an over-write [it / with the record medium of the super-high recording density which has big coercive force] fully since this invention film has the frequency dependence which was excellent in big saturation magnetization and permeability, when it uses as core material of the magnetic head for record is thought, and the industrial meaning is large to a sake.

[Translation done.]